Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/747,805	NARENDRA ET AL.
Examiner	Art Unit
Thien F. Tran	2811

SEARCHED					
Class	Subclass	Date	Examiner		
257	707, 717 719, 778	10/25/2005	тт		
Above	updated	2/23/2006	тт		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		